ChunZheng

High-end Power Semiconductor Manufacturer

KP1250A 400V-800V
Phase Control Thyristor

- High power cycling capability
- Low on-state and switching losses
- Designed for traction and industrial applications

Mean on-state current			I_{TAV}	1250 A	
Repetitive peak off-state voltage			V_{DRM}	400 – 800 V	
Repetitive peak reverse voltage			V_{RRM}		
Turn-off time			t_q	160, 200, 250, 320, 400, 500 μs	
V_{DRM}, V_{RRM}, V	400	500	600	700	800
Voltage code	4	5	6	7	8
T_j, °C	-60 – 150				

MAXIMUM ALLOWABLE RATINGS

Symbols and parameters		Units	Values	Test conditions	
ON-STATE					
I_{TAV}	Mean on-state current	A	1250	T_c=85 °C, Double side cooled 180° half-sine wave; 50 Hz	
I_{TRMS}	RMS on-state current	A	1962.5	T_c=85 °C, Double side cooled 180° half-sine wave; 50 Hz	
I_{TSM}	Surge on-state current	kA	22.0 25.0	T_j=$T_{j\,max}$ T_j=25 °C	180° half-sine wave; t_p=10 ms; single pulse; V_D=V_R=0 V; Gate pulse: I_G=2 A; t_{GP}=50 μs; di_G/dt≥1 A/μs
			23.0 26.0	T_j=$T_{j\,max}$ T_j=25 °C	180° half-sine wave; t_p=8.3 ms; single pulse; V_D=V_R=0 V; Gate pulse: I_G=2 A; t_{GP}=50 μs; di_G/dt≥1 A/μs
I^2t	Safety factor	$A^2s\cdot10^3$	2400 3100	T_j=$T_{j\,max}$ T_j=25 °C	180° half-sine wave; t_p=10 ms; single pulse; V_D=V_R=0 V; Gate pulse: I_G=2 A; t_{GP}=50 μs; di_G/dt≥1 A/μs
			2100 2800	T_j=$T_{j\,max}$ T_j=25 °C	180° half-sine wave; t_p=8.3 ms; single pulse; V_D=V_R=0 V; Gate pulse: I_G=2 A; t_{GP}=50 μs; di_G/dt≥1 A/μs
BLOCKING					
V_{DRM}, V_{RRM}	Repetitive peak off-state and Repetitive peak reverse voltages	V	400–800	$T_{j\,min}$< T_j <$T_{j\,max}$; 180° half-sine wave; 50 Hz; Gate open	
V_{DSM}, V_{RSM}	Non-repetitive peak off-state and Non-repetitive peak reverse voltages	V	500–900	$T_{j\,min}$< T_j <$T_{j\,max}$; 180° half-sine wave; single pulse; Gate open	
V_D, V_R	Direct off-state and Direct reverse voltages	V	0.6·V_{DRM} 0.6·V_{RRM}	T_j=$T_{j\,max}$; Gate open	

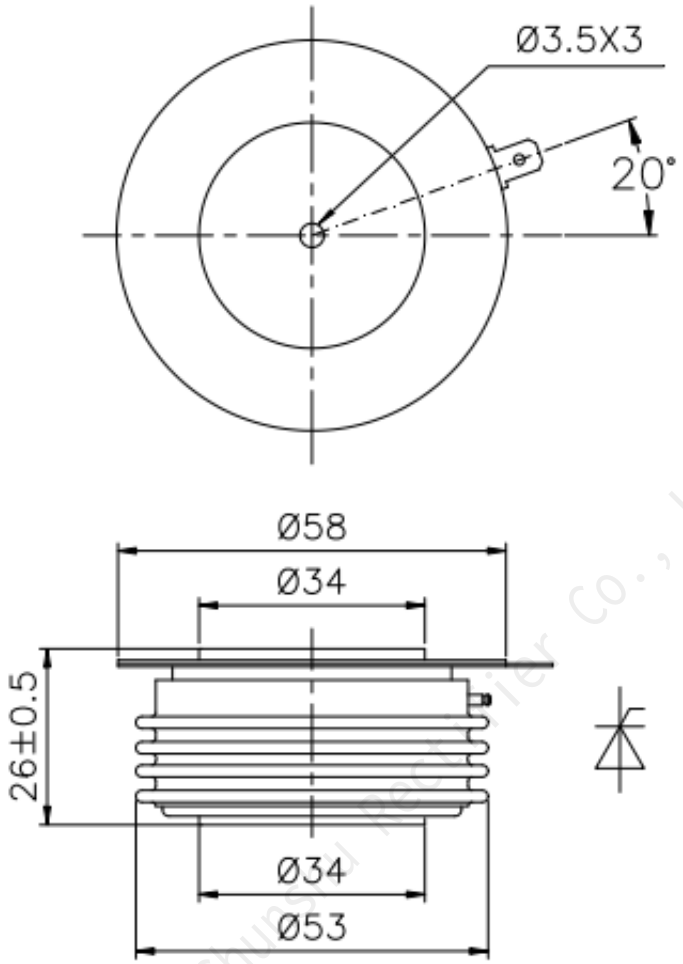
TRIGGERING				
I_{FGM}	Peak forward gate current	A	8	$T_j=T_{j\,max}$
V_{RGM}	Peak reverse gate voltage	V	5	
P_G	Gate power dissipation	W	4	$T_j=T_{j\,max}$ for DC gate current
SWITCHING				
$(di_T/dt)_{crit}$	Critical rate of rise of on-state current non-repetitive (f=1 Hz)	A/μs	800	$T_j=T_{j\,max}$; $V_D=0.67\cdot V_{DRM}$; I_{TM}=3500 A; Gate pulse: I_G=2 A; t_{GP}=50 μs; $di_G/dt\geq 2$ A/μs
THERMAL				
T_{stg}	Storage temperature	°C	-60…50	
T_j	Operating junction temperature	°C	-60…150	
MECHANICAL				
F	Mounting force	kN	14.0…16.0	
a	Acceleration	m/s^2	50	Device clamped

CHARACTERISTICS

Symbols and parameters		Units	Values	Conditions	
ON-STATE					
V_{TM}	Peak on-state voltage, max	V	1.75	T_j=25 °C; I_{TM}=3925 A	
$V_{T(TO)}$	On-state threshold voltage, max	V	0.920	$T_j=T_{j\,max}$;	
r_T	On-state slope resistance, max	mΩ	0.197	$0.5\,\pi\,I_{TAV} < I_T < 1.5\,\pi\,I_{TAV}$	
I_L	Latching current, max	mA	1000	T_j=25 °C; V_D=12 V; Gate pulse: I_G=2 A; t_{GP}=50 μs; $di_G/dt\geq 1$ A/μs	
I_H	Holding current, max	mA	300	T_j=25 °C; V_D=12 V; Gate open	
BLOCKING					
I_{DRM}, I_{RRM}	Repetitive peak off-state and Repetitive peak reverse currents, max	mA	100	$T_j=T_{j\,max}$; $V_D=V_{DRM}$; $V_R=V_{RRM}$	
$(dv_D/dt)_{crit}$	Critical rate of rise of off-state voltage[1], min	V/μs	200, 320, 500, 1000, 1600, 2000, 2500	$T_j=T_{j\,max}$; $V_D=0.67\cdot V_{DRM}$; Gate open	
TRIGGERING					
V_{GT}	Gate trigger direct voltage, max	V	2.50 1.50	T_j=25 °C $T_j=T_{j\,max}$	V_D=12 V; I_D=3 A; Direct gate current
I_{GT}	Gate trigger direct current, max	mA	250 150	T_j= 25 °C $T_j=T_{j\,max}$	
V_{GD}	Gate non-trigger direct voltage, min	V	0.55	$T_j=T_{j\,max}$; $V_D=0.67\cdot V_{DRM}$; Direct gate current	
I_{GD}	Gate non-trigger direct current, min	mA	70.00		
SWITCHING					
t_{gd}	Delay time, max	μs	0.85	T_j=25 °C; V_D=600 V; $I_{TM}=I_{TAV}$; di/dt=200 A/μs; Gate pulse: I_G=2 A; V_G=20 V; t_{GP}=50 μs; di_G/dt=2 A/μs	
t_{gt}	Turn-on time, max	μs	4.00		
t_q	Turn-off time[2], max	μs	160, 200, 250, 320, 400, 500	dv_D/dt=50 V/μs; $T_j=T_{j\,max}$; $I_{TM}=I_{TAV}$; di_R/dt=-10 A/μs; V_R=100V; $V_D=0.67\cdot V_{DRM}$	
Q_{rr}	Total recovered charge, max	μC	1100	$T_j=T_{j\,max}$; I_{TM}=1250 A; di_R/dt=-10 A/μs; V_R=100 V	
t_{rr}	Reverse recovery time, max	μs	18		
I_{rrM}	Peak reverse recovery current, max	A	122		

THERMAL					
R_{thjc}	Thermal resistance, junction to case, max	°C/W	0.030	Direct current	Double side cooled
R_{thjc-A}			0.066		Anode side cooled
R_{thjc-K}			0.054		Cathode side cooled
R_{thck}	Thermal resistance, case to heatsink, max	°C/W	0.006	Direct current	
MECHANICAL					
w	Weight, max	g	210		
D_s	Surface creepage distance	mm (inch)	7.86 (0.309)		
D_a	Air strike distance	mm (inch)	6.10 (0.240)		

OVERALL DIMENSIONS



KT40

All dimensions in millimeters

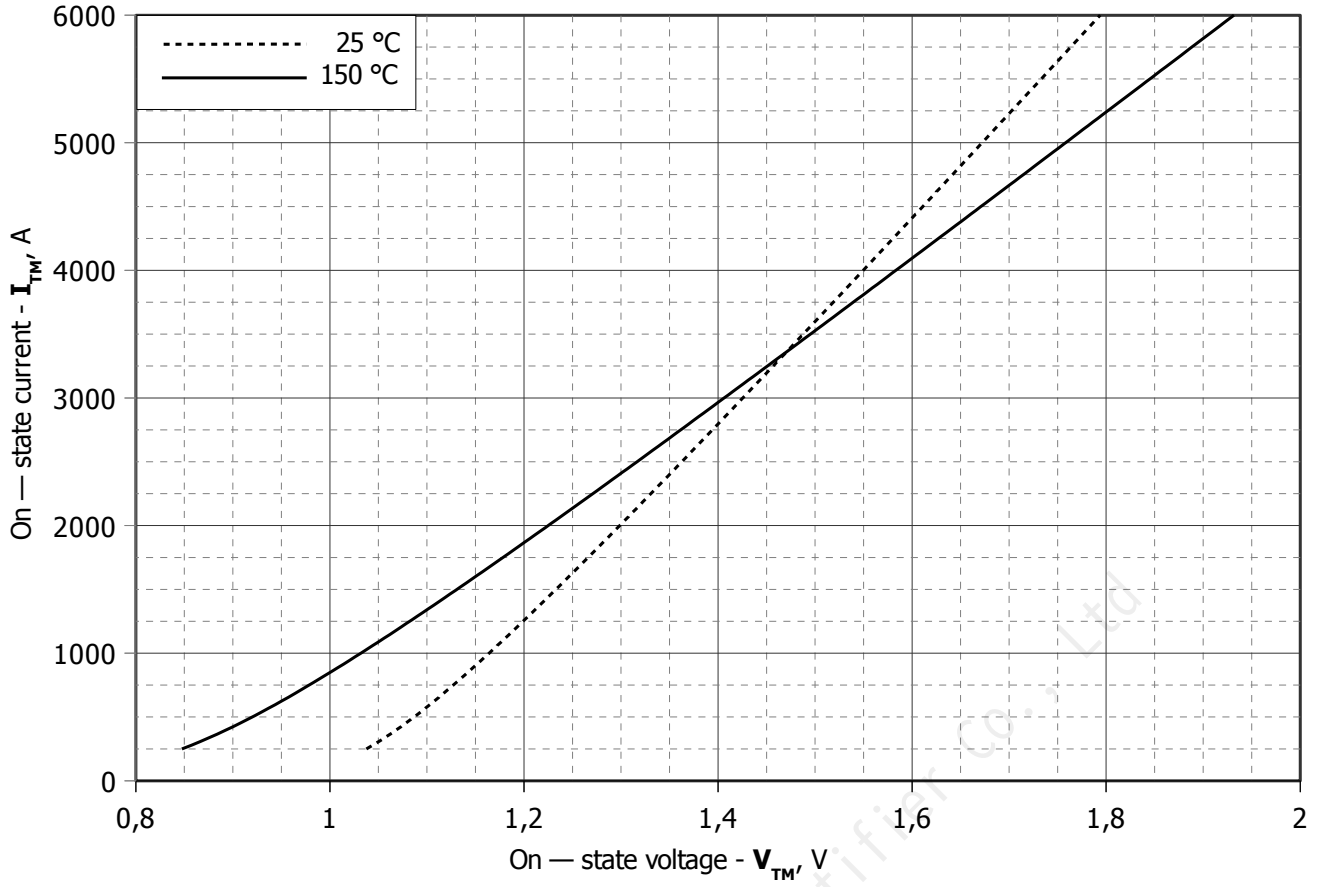


Fig 1 – On-state characteristics of Limit device

Analytical function for On-state characteristic:

$$V_T = A + B \cdot i_T + C \cdot \ln(i_T + 1) + D \cdot \sqrt{i_T}$$

	Coefficients for max curves	
	$T_j = 25°C$	$T_j = T_{j\,max}$
A	0.82795000	0.51947000
B	0.00012036	0.00017283
C	0.03462400	0.05552300
D	-0.00074257	-0.00139100

On-state characteristic model (see Fig. 1)

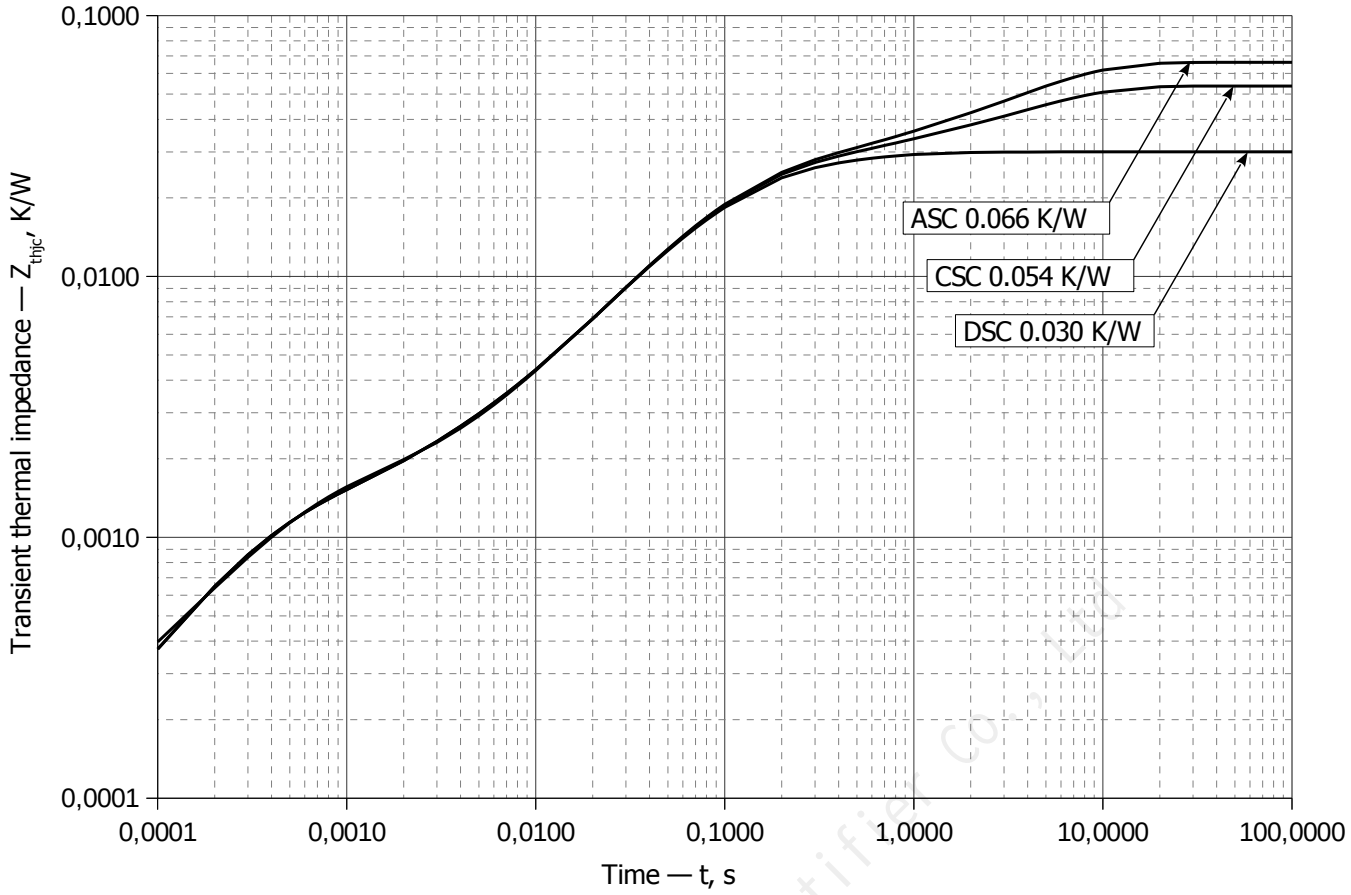


Fig 2 – Transient thermal impedance Z_{thjc} vs. time t

Analytical function for Transient thermal impedance junction to case Z_{thjc} for DC:

$$Z_{thjc} = \sum_{i=1}^{n} R_i \left(1 - e^{-\frac{t}{\tau_i}}\right)$$

Where ***i*** = 1 to ***n***, ***n*** is the number of terms in the series.

t = Duration of heating pulse in seconds.

Z_{thjc} = Thermal resistance at time t.

R_i = Amplitude of p_{th} term.

τ_i = Time constatnt of r_{th} term.

DC Double side cooled

i	1	2	3	4	5	6
R_i, K/W	0.0007052	0.01986	0.001443	0.006652	0.001253	0.00009733
τ_i, s	1.200	0.083	0.0205	0.350	0.0004173	0.000001

DC Anode side cooled

i	1	2	3	4	5	6
R_i, K/W	0.03615	0.006266	0.0178	0.004365	0.0004912	0.001067
τ_i, s	4.713	0.5062	0.09497	0.04557	0.002123	0.0002807

DC Cathode side cooled

i	1	2	3	4	5	6
R_i, K/W	0.001065	0.0004934	0.004583	0.01764	0.006202	0.0237
τ_i, s	0.0002798	0.002114	0.04598	0.09501	0.4891	4.712

Transient thermal impedance junction to case Z_{thjc} model (see Fig. 2)

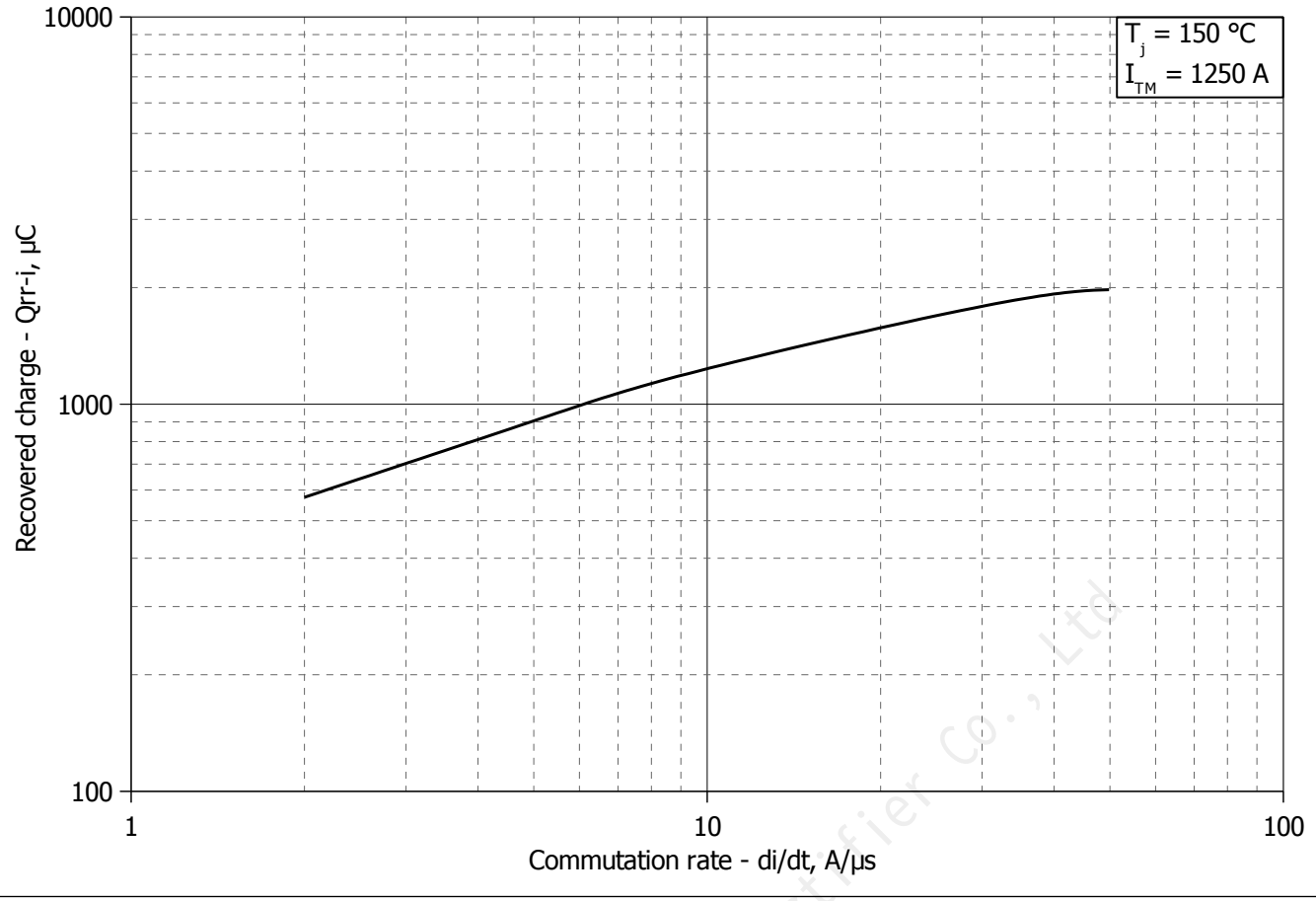


Fig 3 – Maximum recovered charge Q_{rr-i} (integral) vs. commutation rate di_R/dt

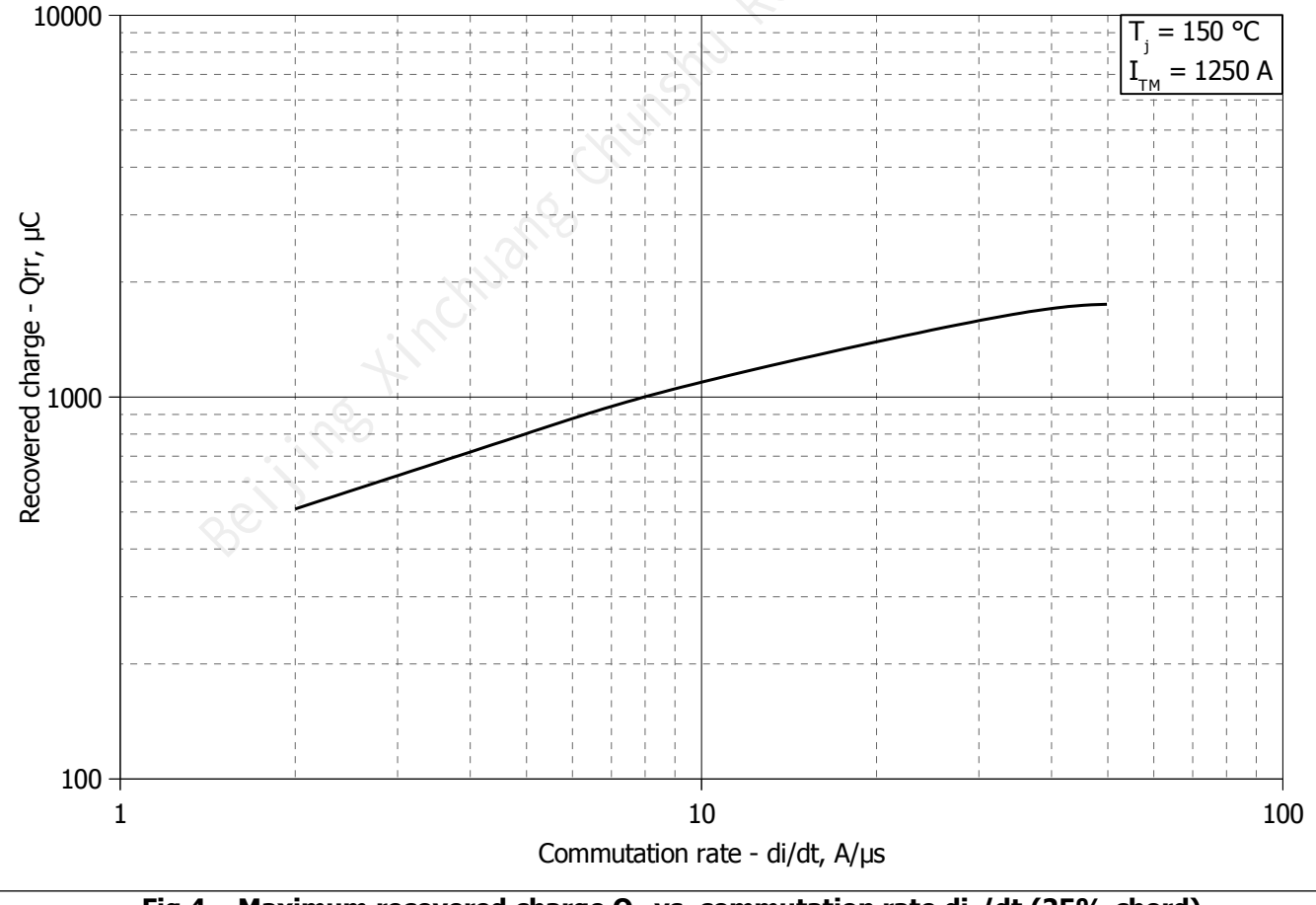


Fig 4 – Maximum recovered charge Q_{rr} vs. commutation rate di_R/dt (25% chord)

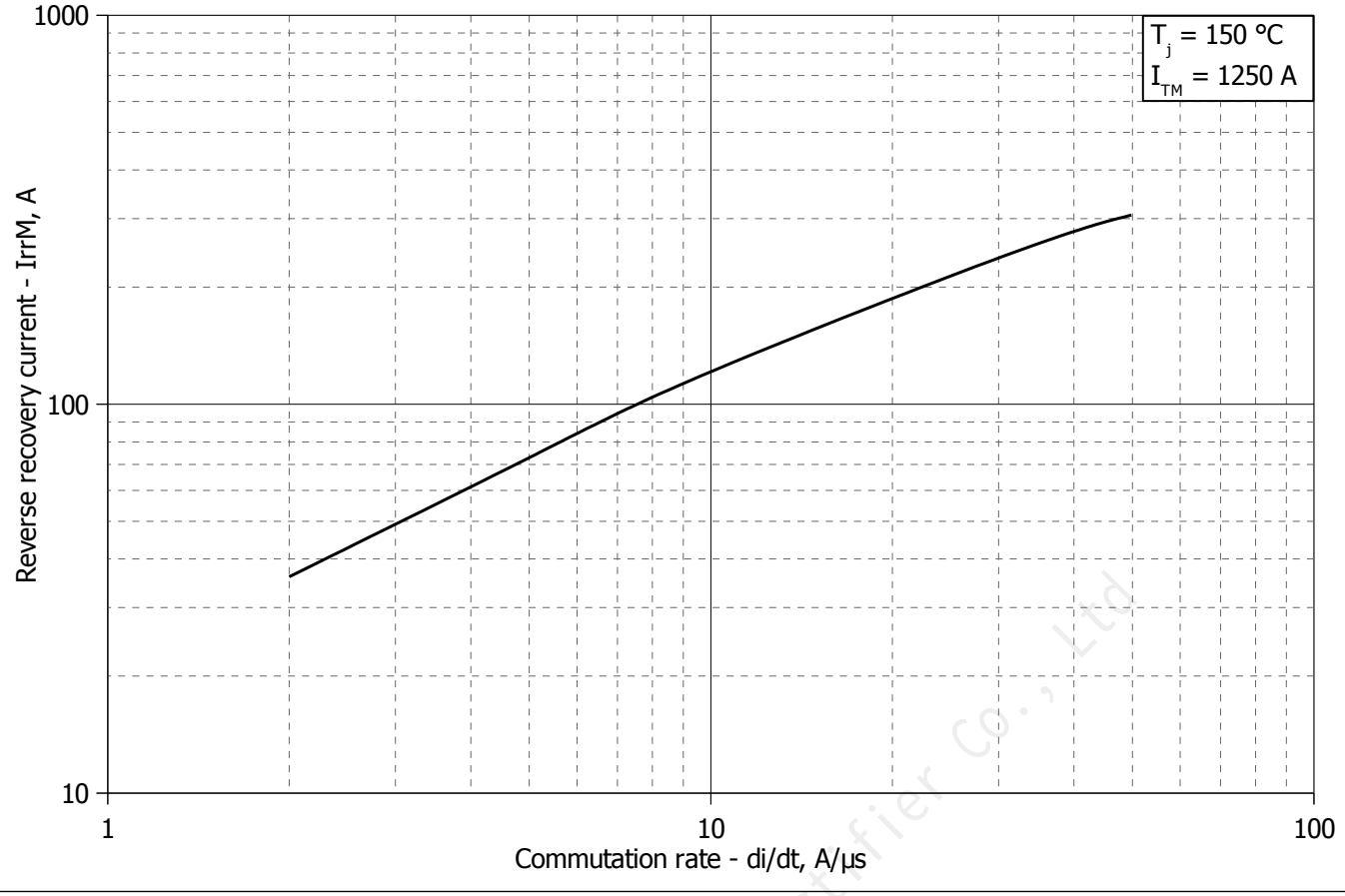


Fig 5 – Maximum reverse recovery current I_{rrM} vs. commutation rate di_R/dt

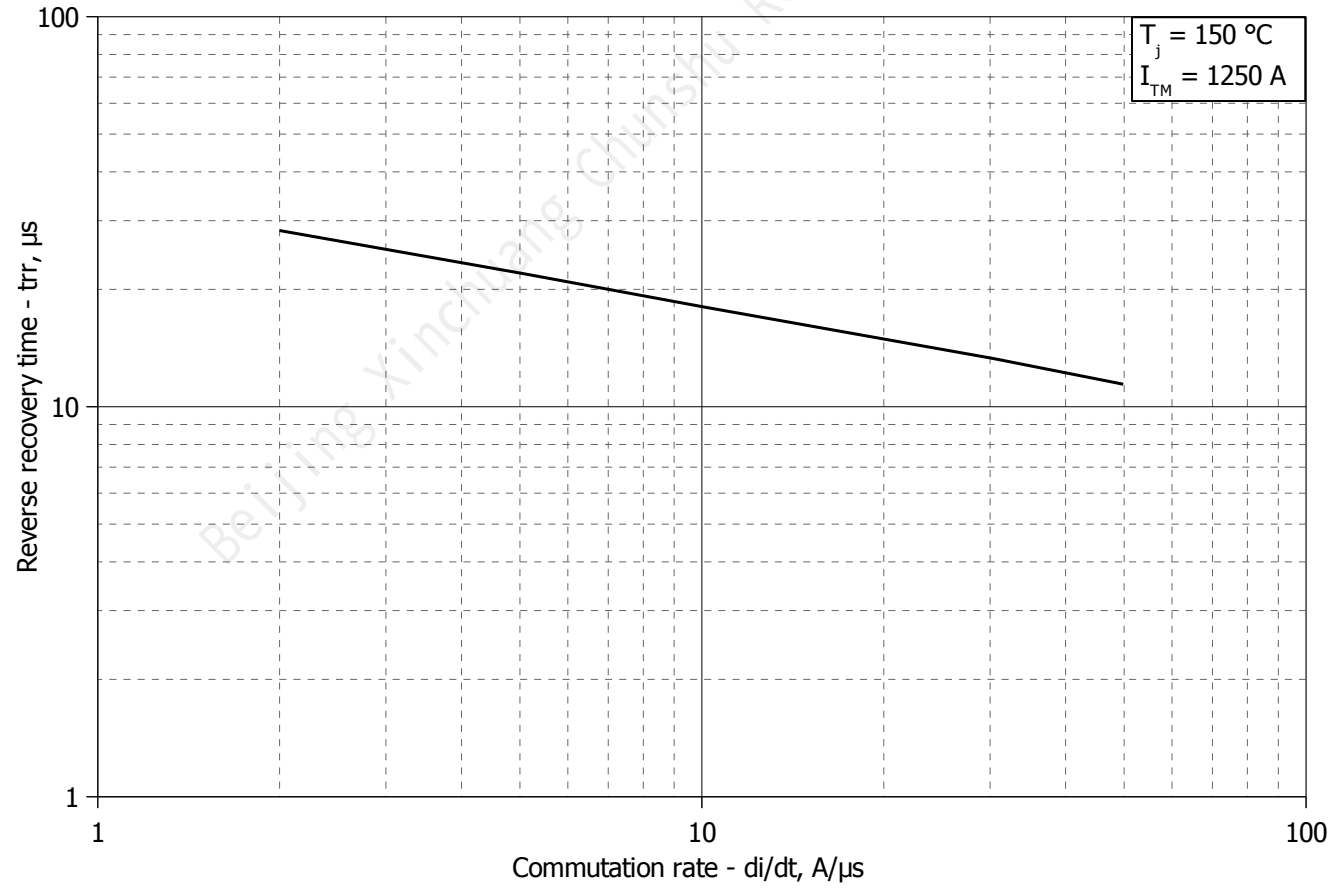


Fig 6 – Maximum recovery time t_{rr} vs. commutation rate di_R/dt (25% chord)

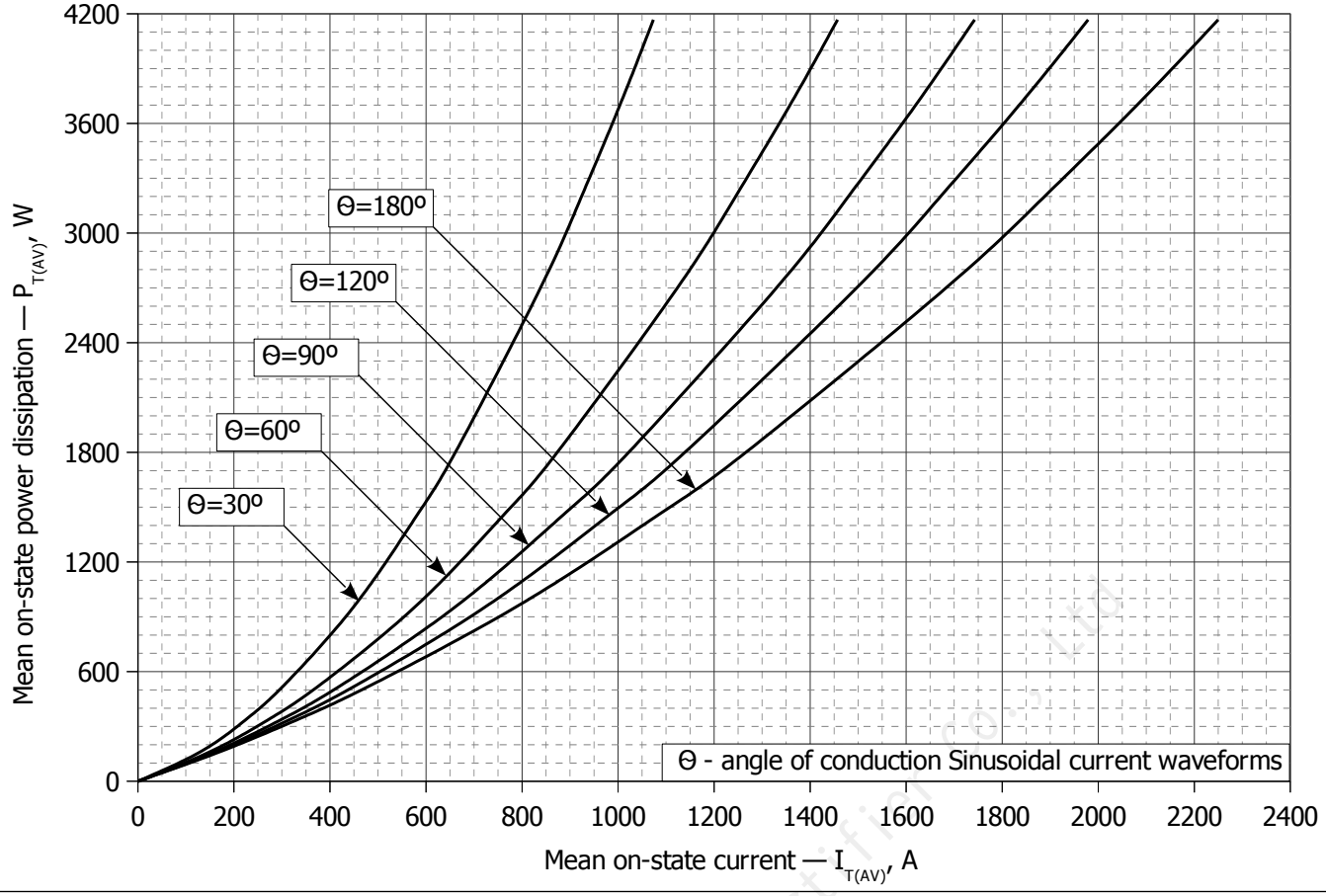


Fig. 7 - Mean on-state power dissipation P_{TAV} vs. mean on-state current I_{TAV} for sinusoidal current waveforms at different conduction angles (f=50Hz, DSC)

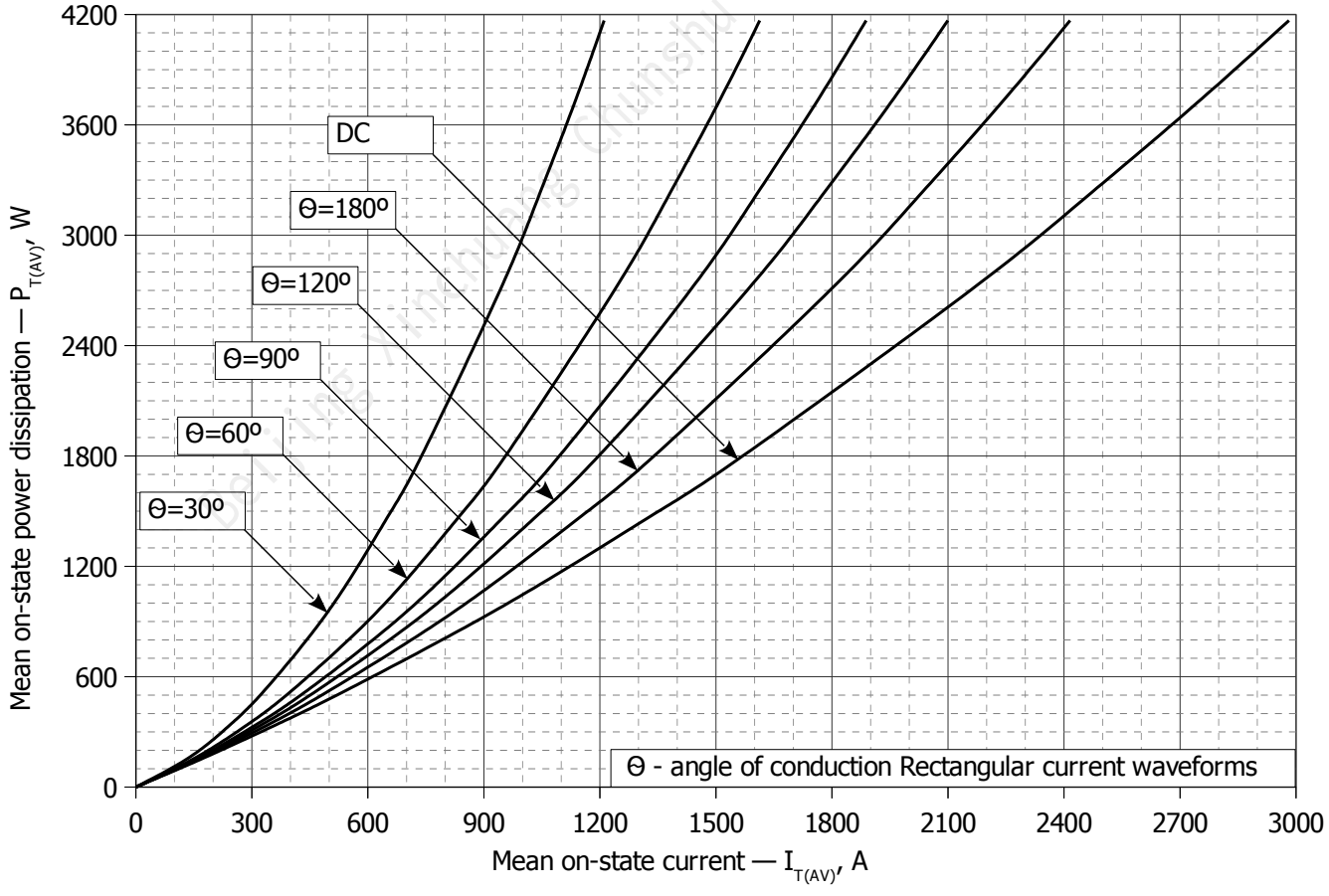


Fig. 8 – Mean on-state power dissipation P_{TAV} vs. mean on-state current I_{TAV} for rectangular current waveforms at different conduction angles and for DC (f=50Hz, DSC)

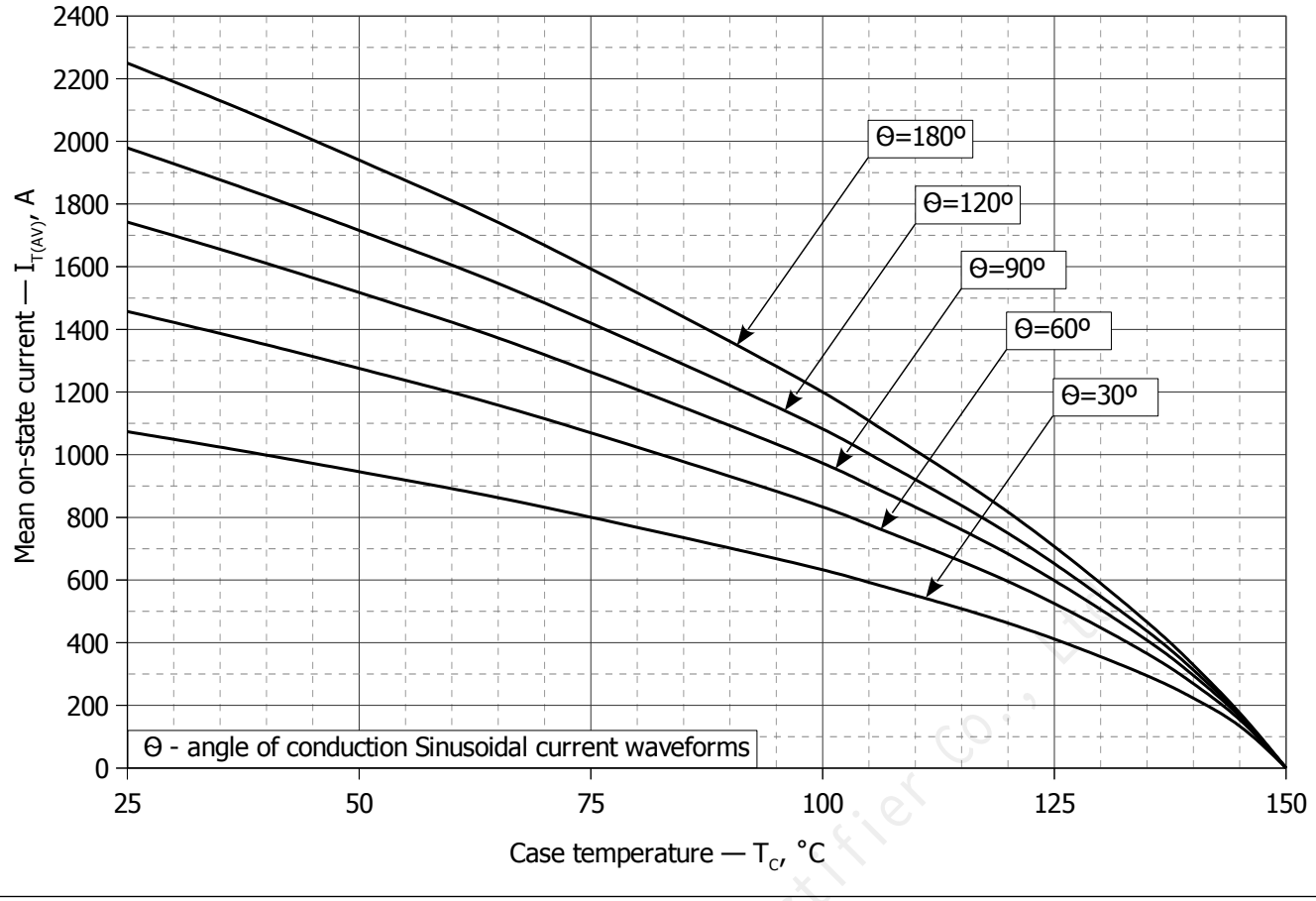


Fig. 9 – Mean on-state current I_{TAV} vs. case temperature T_C for sinusoidal current waveforms at different conduction angles (f=50Hz, DSC)

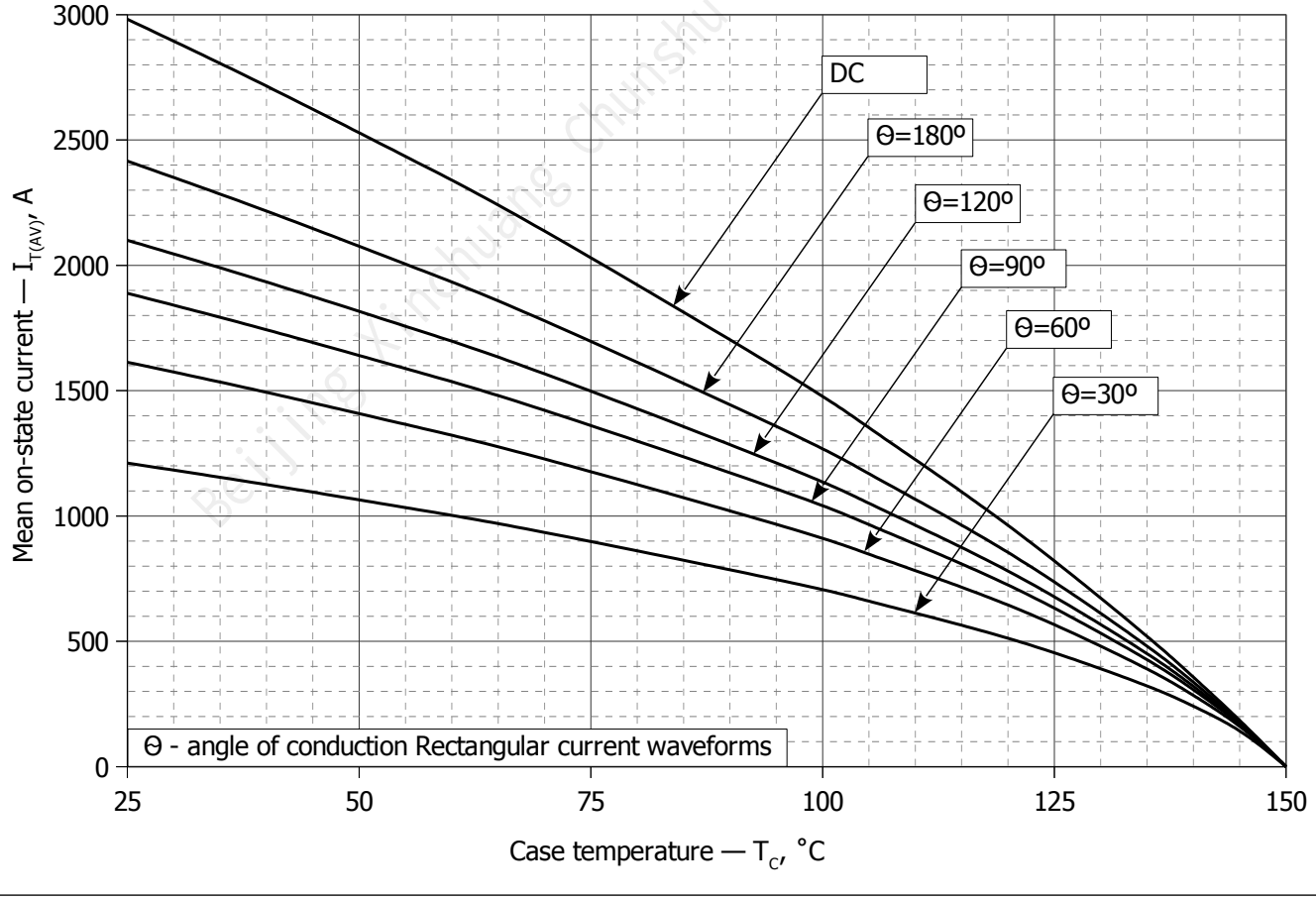


Fig. 10 - Mean on-state current I_{TAV} vs. case temperature T_C for rectangular current waveforms at different conduction angles and for DC (f=50Hz, DSC)

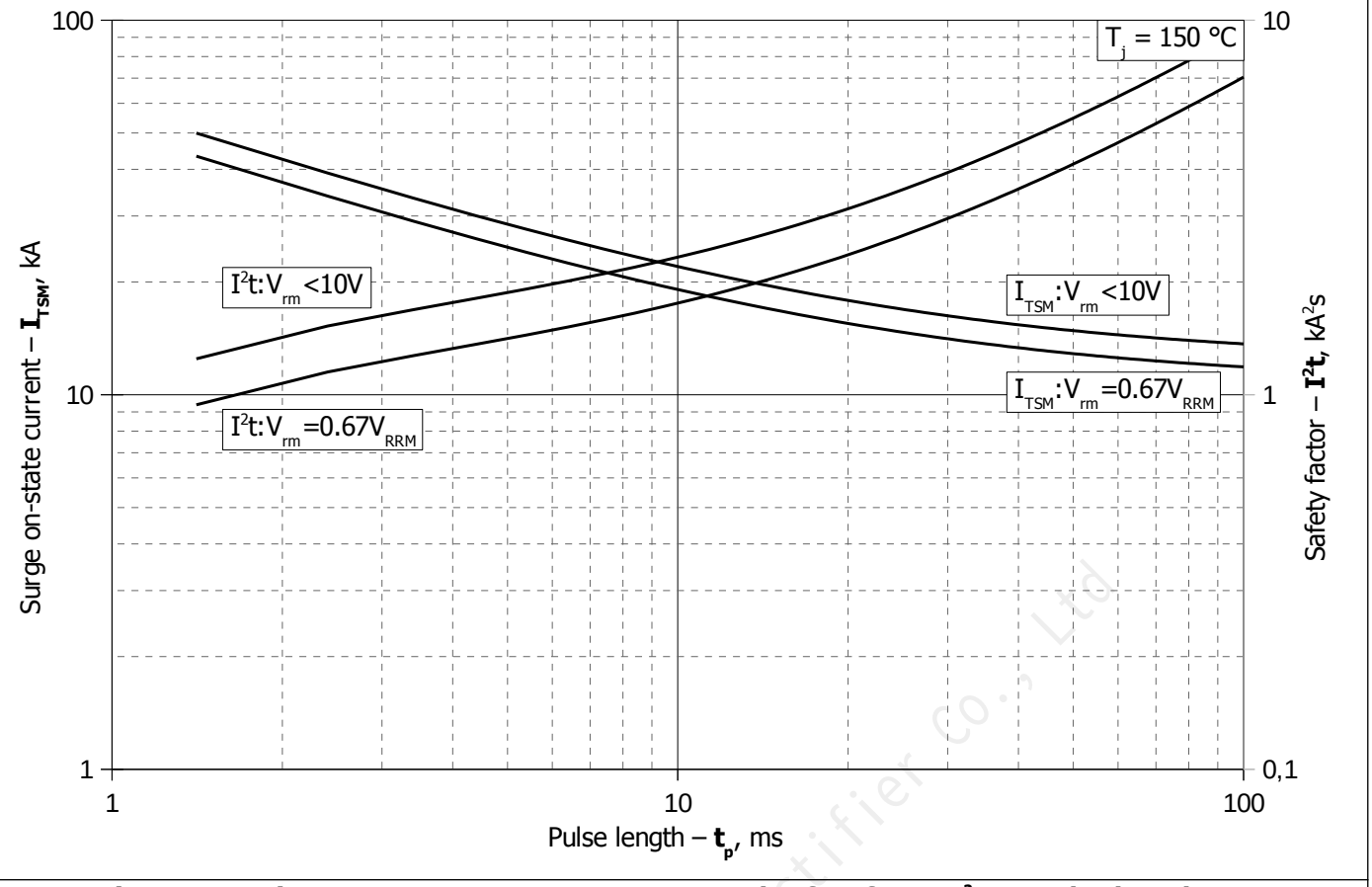


Fig. 11 – Maximum surge on-state current I_{TSM} and safety factor I^2t vs. pulse length t_p

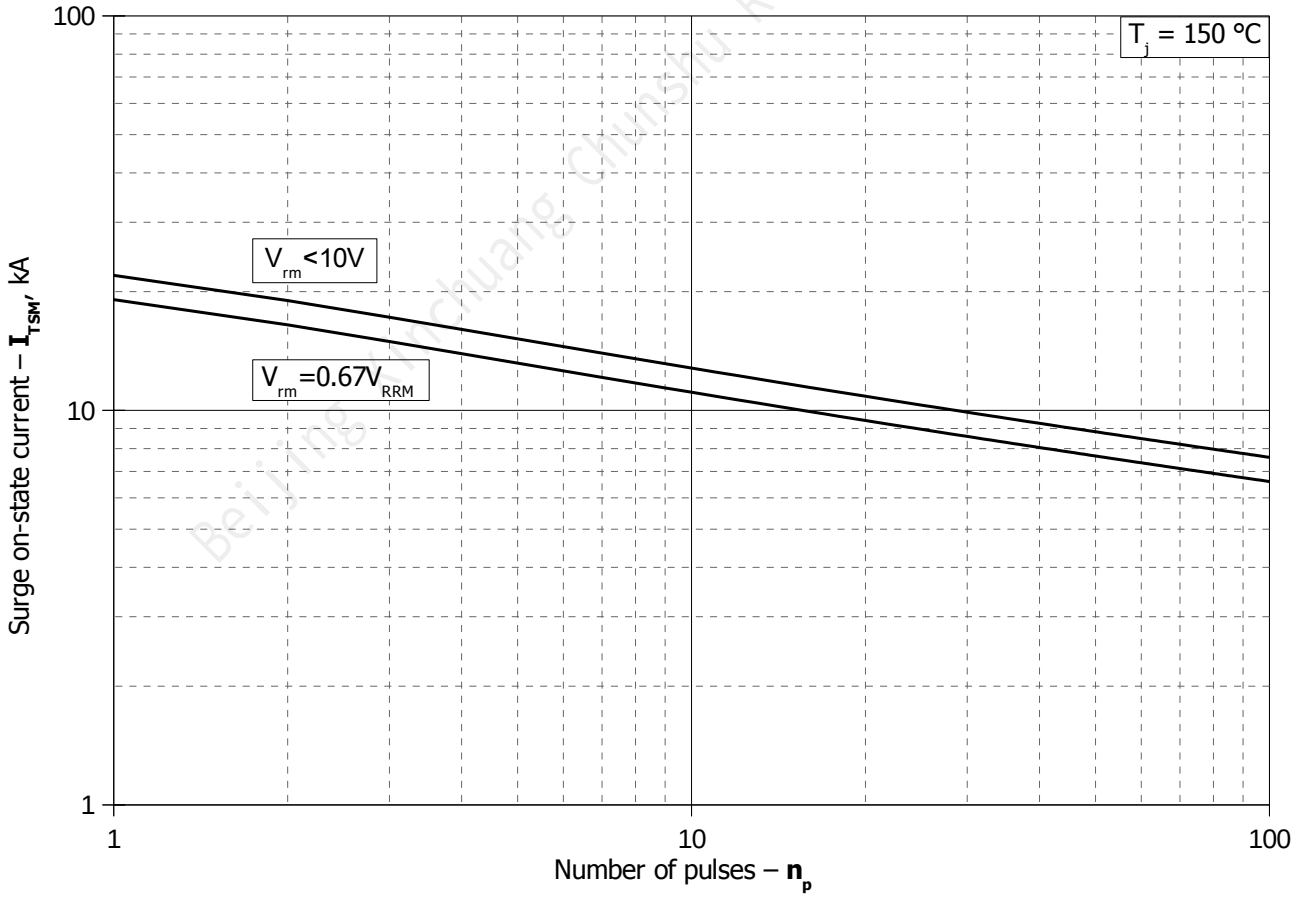


Fig. 12 - Maximum surge on-state current I_{TSM} vs. number of pulses n_p

